

# **IEEE SW Test Workshop**

Semiconductor Wafer Test Workshop

**Jerry Broz, Ph.D.**  
General Chair  
IEEE SW Test Workshop



# **Welcome to the IEEE SW Test Workshop**



IEEE COMPONENTS, PACKAGING AND  
MANUFACTURING TECHNOLOGY SOCIETY

**June 8 to 11, 2008**  
**San Diego, CA USA**

# 18<sup>th</sup> Annual SWTW



Paradise Point and Spa, San Diego, CA



June 8 to 11, 2008

IEEE SW Test Workshop

# IEEE SW-Test Workshop

- SW Test IS a Probe Technology Forum ...
  - It is **“THE”** Conference for Wafer Test Professionals
  - Practical solutions to real problems
  - A balance mixture of semiconductor manufacturer and supplier presentations
- Informal Conference ...
  - Great social activities and informal discussions
  - Meet new people and have a little fun !



# IEEE SW-Test Workshop

- Sponsored by the IEEE Components, Packaging and Manufacturing Technology (CPMT) Society
- Leading international forum for scientists and engineers engaged in the research, design and development of revolutionary advances in micro-systems packaging and manufacture.

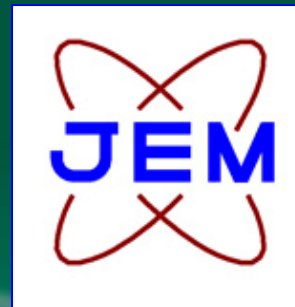
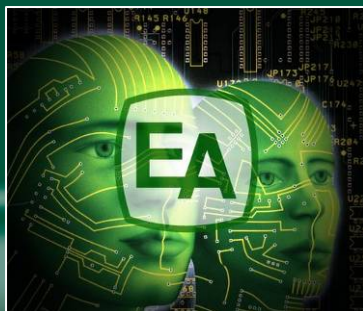


# What's New for 2008 ?

- Record Number of Submissions ...
  - 9 Technical Sessions
    - Total of 31 Podium Presentations
  - 2 Poster Sessions
    - Total of 10 Poster Presentations
- Products / Services EXPO – 2008
  - Expanded to 52 full size booths
  - **SOLD OUT !** (... thanks ! ...)



# Corporate Supporter Program



# “How’s My Driving?”

- Organization and Technical Program ...
  - Jerry Broz, Ph.D., International Test Solutions, General Chair
  - William Mann, Chair Emeritus and Social Coordinator
  - Brett Crump, Micron Technology, Program Chair
  - Maddie Harwood, CEM Inc, Registration and Finance Chair
  - Meredith Griffith, CEM Inc., Exhibits / Registration Coordinator

## Program Committee and Steering Committee

- Ken Karklin, Touchdown Technologies
- Patrick Mui, JEM America
- Roger Sinsheimer, Xandex
- Fred Taber, BiTS Workshop
  - Proceedings Coordinator
- Warren “Stu” Crippen, Intel
- Nadine Aldahhan, Freescale
- Jack Courtney, IBM
- Ger Koch, NXP Semiconductor
- Michael Egloff, AMD
- Michael Harris, Texas Instruments
- Rey Rincon, Consultant



# Technical Program / Agenda

- Sunday, June 8, 2008
  - Tutorial w/ 3 presentations
  - Registration and Cocktails
  - Dinner
  - Probe Year In Review
  - Keynote ...



**“Wafer Test Industries Impact on ATE”**

**Debbora Ahlgren**

Vice President & Chief Marketing Officer  
Verigy, Inc.





# Technical Program / Agenda

- Monday, June 9
  - Continental Breakfast
  - MEMS for Production-Level Probing
  - Advances in Traditional Probe Card Technologies
  - Lunch
  - Improving Test Cell Performance
  - Power and High Voltage
  - Exhibits Open From 5:00 to 8:00 PM
    - Carving stations and hors d'oeuvres served
  - Vendor “Press Time” / Sponsored Events
  - Socializing at the Barefoot Bar



# Technical Program / Agenda

- Tuesday, June 10
  - Continental Breakfast
  - Large Array Probing
  - Probe Potpourri
  - Lunch (Outdoor, weather permitting, Lawn BBQ)
  - Probe Card Cleaning Practices
  - Exhibits Open from 3:00 to 5:00 PM
  - Two Technical Poster Sessions
    - Session 01 - 3:00 to 3:30 PM
    - Session 02 - 3:30 to 4:00 PM
  - Midway Museum for reception, dinner, tours
    - Buses depart for Midway Museum at 6:00PM



# Tuesday Social

- Relaxed networking
- Private Reception and Buffet Dinner
- Tours, Simulators, FUN !



# Technical Program / Agenda

- Wednesday, June 11
  - Continental Breakfast
  - Strategic Design Methodologies
  - Probe Challenges
  - Best Presentations Awards
  - Adjournment and Lunch



# Recognition & Awards

- Best Overall Presentation
- Best Data Presented
- Most “Inspirational” Presentation
- Best Presentation, Tutorial in Nature
  
- Other “Special Awards”



# SWTW-2007 Awards

## Best Overall Presentation

"ROUTE60™ : A New Vertical Probing Technology"

Roberto Crippa

Stefano Lazzari

**Technoprobe, S.p.A**

Raffaele Vallauri

Massimo Gervasoni

**STMicroelectronics**



## Best Data Presentation

"Electrical Contact Resistance - The Key Parameter in Probe Card Performance"

January Kister

Steve Hopkins

**Microprobe, Inc.**



# SWTW-2007 Awards

## Most Inspirational Presentation

*“Thin Film Interposer Probes in Production”*

Chris Sullivan

John Hagios

Steve Duda

Sally Francis

**IBM Microelectronics**



## Best Presentation, Tutorial in Nature

*“Taguchi's Method for Probe Card Development”*

Vincent Reynaud

**Mesatronics**



# SWTW-2007 Awards

## Best Poster Presentation

*“Design Considerations for Parametric-RF Probing  
in Production Test Environments”*

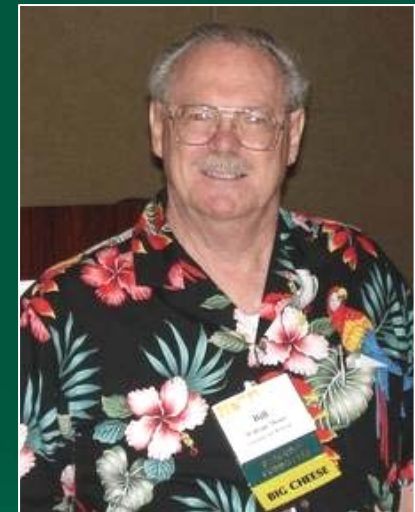
Roger Hayward  
Bob Hansen  
Cascade MicroTech



## Lifetime Achievement Award

Presented to ...

William Mann  
SW-Test Workshop  
Founder and Chair Emeritus





# The “Special” Award



“What A Load  
Of Crap !”

For the Poorest  
Disguised Sales  
Pitch

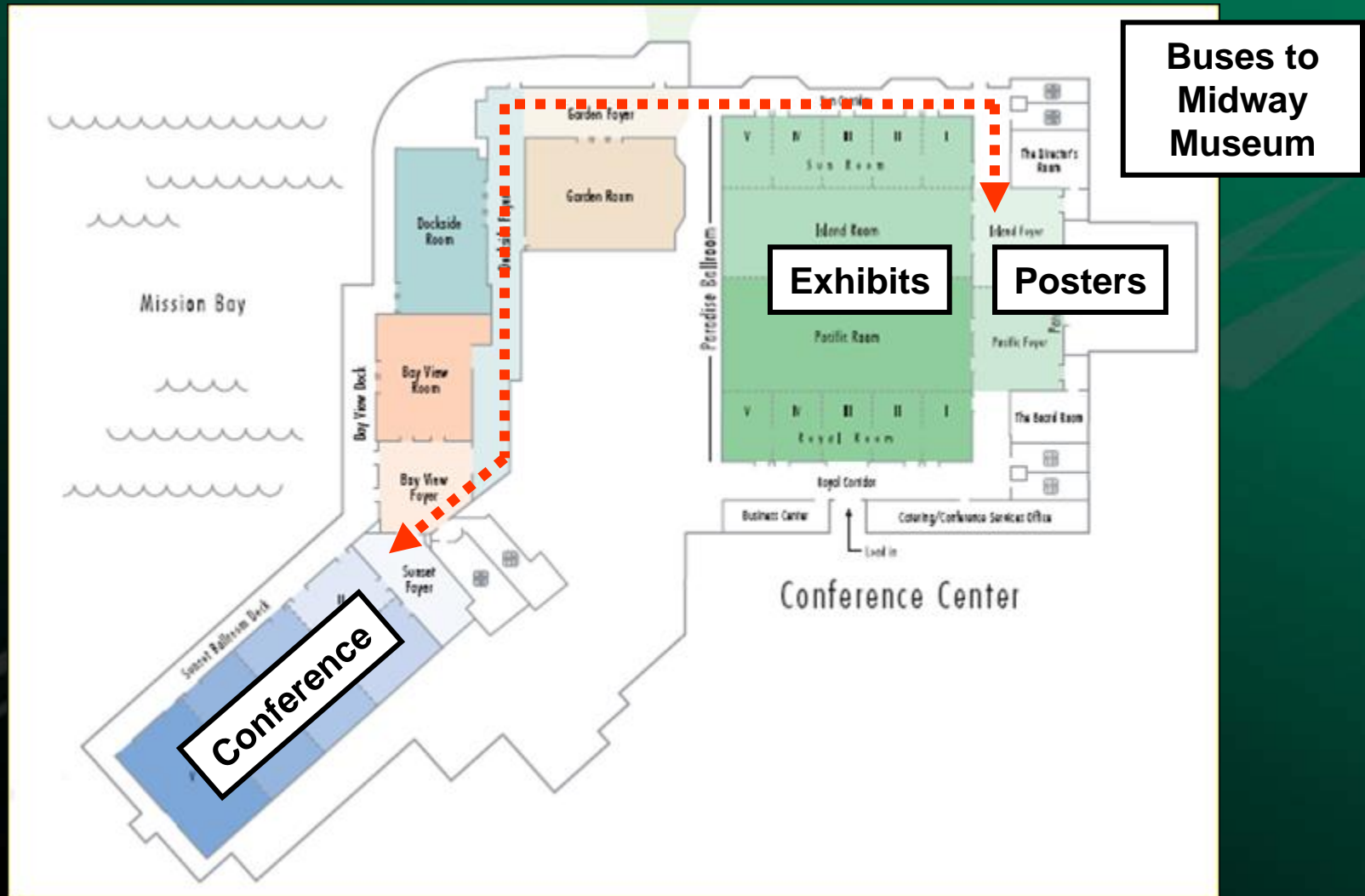
*“What happens at SWTW stays at SWTW !”*

# IEEE SW Test EXPO 2008

## Exhibitor Booklet will be Available

1. AMST CO., LTD
2. Taconic
3. **Hyphenated-Systems** *(corp. supporter)*
4. Salland Engineering B.V.
5. ERS America
6. **BucklingBeam Solutions LLC** *(corp. supporter)*
7. **International Test Solutions** *(corp. supporter)*
8. Left Coast Instruments
9. Accuprobe, Inc.
10. Electroglas, Inc.
11. **Electronic Apparatus NV** *(corp. supporter)*
12. **Cascade Microtech** *(corp. supporter)*
13. MicroProbe
14. SV Probe, Inc.
15. Oxford Lasers, Inc.
16. TSE Co., Ltd.
17. Tokyo Electron Limited (TEL)
19. **Micronics Japan Co., Ltd.** *(corp. supporter)*
20. Air Products & Chemicals, Inc.
21. Wentworth Laboratories, Inc.
22. Integrated Technology Corporation
23. **Feinmetall GmbH** *(corp. supporter)*
24. NHK Spring Co., Ltd
25. inTEST Silicon Valley Corporation
26. Probe Logic
27. Beijert Engineering
28. OptimalTest Ltd.
30. R&D Circuits
31. Integrated Test Corporation
32. Dynamic Test Solutions - DTS
33. **FormFactor** *(corp. supporter)*
34. **JEM America Corp.** *(corp. supporter)*
35. Synergetix
36. Camtek USA
37. Scanimetrics
38. Xena Technologies
39. SUSS MicroTec Inc.
40. Topcon
41. ToTo U.S.A., Inc.
42. Cognex Corporation
43. **Rudolph Technologies** *(corp. supporter)*
44. Technoprobe SPA
45. ICOS Vision Systems, Inc.
46. Everett Charles Technologies (ECT)
47. Qualitau, Inc.
48. Fima SRL
49. International Contact Technologies Inc.
50. Xpress Test Solutions
51. Apex America, Inc.
52. Instec Inc.
53. T.I.P.S. Messtechnik GmbH

# Don't Get Lost !



Buses to  
Midway  
Museum

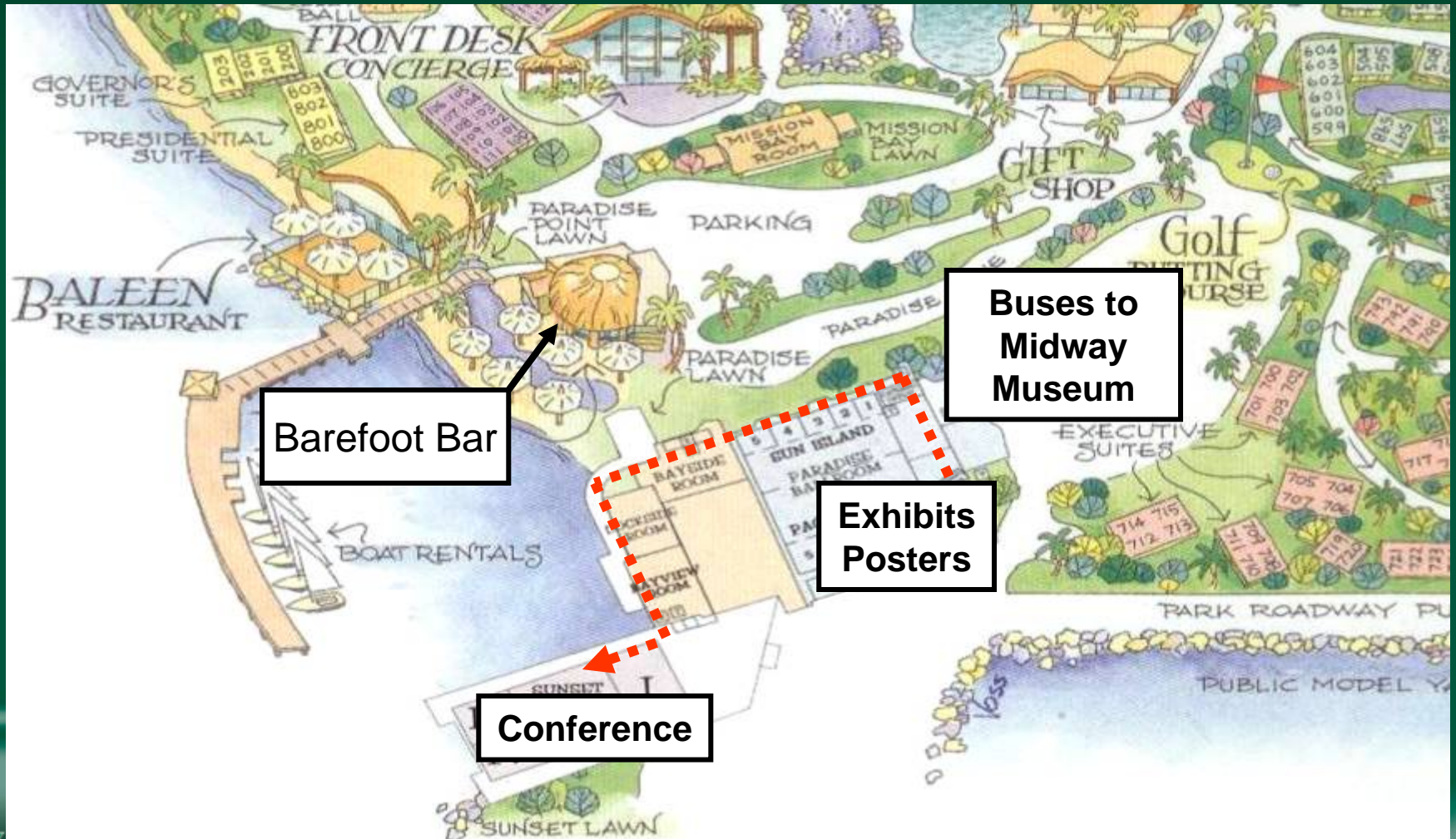
Exhibits

Posters

Conference

Conference Center

# Don't Get Lost in Paradise !



# <http://www.swtest.org>

- Central Online Repository
  - Past presentations
  - Online registration
  - Most current news for SW Test Workshop
  - Sign up for our mailing list
- Tremendous continued success !!
  - Over 115K visits !



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# Want to Learn More ?

- **Burn In & Test Socket Workshop**  
Mesa, Arizona



- **IS-Test Workshop**  
Freising, Germany



- **Global STC Conference**  
San Diego, California



- **Electronic Components and Technology Conference**  
Orlando, Florida

